OPTIMIZATION OF A LASER-PLASMA-BASED X-RAY SOURCE FOR ABSORPTION SPECTROSCOPY DIAGNOSTIC OF WARM DENSE MATTER

Martynenko A.S.,[*1] ***Pikuz S.A.,***[1,2] ***Skobelev I.Yu.,***[1,2] ***Ryazantsev S.N.,***[1,2] ***Baird C.,***[3] ***Booth N.,***[4] ***Doehl L.Â ,***[3] ***Durey P.,***[3] ***Faenov A.Ya.,***[1,5] ***Farley D.,***[3] ***Kodama R.,***[4,5] ***Lancaster K.,***[3] ***Mckenna P.,***[7] ***Murphy C.D.,***[3] ***Spindloe C.,***[4] ***Pikuz T.A.,***[1,5] ***Woolsey N.***[3]

[1]*JIHT RAS, Moscow, Russia,* [2]*MEPhI, Moscow, Russia,* [3]*UOY, York, United Kingdom (Great Britain),* [4]*CLF RAL, Didcot, United Kingdom (Great Britain),* [5]*ORTI OU, Osaka, Japan,* [6]*ILE, Osaka, Japan,* [7]*UoS, Department of Physics, SUPA, University of Strathc, United Kingdom (Great Britain)*

**artmarty@mail.ru*

X-ray absorption spectroscopy (XAS) [1] diagnostic has been proved to be an effective tool for warm dense matter (WDM) experimental studies. However, XAS requires a short-lived X-ray source (XRS) of sufficiently high emissivity and the absence of intense characteristic lines in a spectral range of interest. In our recent study [2], we discussed choosing its optimum material and thickness to get a bright source in the wavelength range of 2-6 Å (2-6 keV) considering relatively low-Z elements. We demonstrated that the so-called photorecombination region of X-ray characteristic spectral emission is best suited for XAR using a laser-generated X-ray source, due to its featureless spectra of high intensity. Performed experiments showed that the highest emissivity of solid aluminium and silicon foil targets irradiated with a 1 ps high-contrast sub-kJ laser pulse of Vulcan PW laser facility is achieved when the target thickness is close to 10 μm. An outer plastic layer increases the emissivity even further [3].

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